Lecture Stat 461-561 Wald, Rao and Likelihood Ratio Tests

AD

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- **•** Introduction
- Wald test
- **•** Rao test
- Likelihood ratio test
- We want to test H_0 : $\theta = \theta_0$ against H_1 : $\theta \neq \theta_0$ using the log-likelihood function.
- We denote $I(\theta)$ the loglikelihood and $\widehat{\theta}_n$ the consistent root of the likelihood equation.
- **•** Intuitively, the farther $\widehat{\theta}_n$ is from θ_0 , the stronger the evidence against the null hypothesis.
- How far is "far enough"?

 \bullet We use the fact that under regularity assumptions we have under H_0

$$
\sqrt{n}\left(\widehat{\theta}_{n}-\theta_{0}\right)\xrightarrow{D}\mathcal{N}\left(0,I^{-1}\left(\theta_{0}\right)\right)
$$

where

$$
I(\theta_0) = \mathbb{E}_{\theta_0} \left[\frac{\partial^2 \log f(X|\theta)}{\partial \theta^2} \right].
$$

• This suggests defining the following Wald statistic

$$
W_n = \sqrt{n I(\theta_0)} \left(\widehat{\theta}_n - \theta_0\right)
$$

or $\mathcal{W}_n = \sqrt{n\widehat{I}\left(\theta_0\right)}\left(\widehat{\theta}_n - \theta_0\right)$ where $\widehat{I}\left(\theta_0\right)$ is a consistent estimate of $I(\theta_0)$, e.g. $I(\widehat{\theta}_n)$.

 \bullet Under H_0 , we have

$$
W_n = \sqrt{n\hat{l}(\theta_0)} \left(\widehat{\theta}_n - \theta_0\right) \xrightarrow{D} \mathcal{N}(0, 1)
$$

- A Wald test is any test that rejects H_0 : $\theta = \theta_0$ in favor of H_1 : $\theta \neq \theta_0$ when $|W_n| \geq z_{\alpha/2}$ where $z_{\alpha/2}$ satisfies $P(Z \ge z_{\alpha/2}) = \alpha/2.$
- It follows that by construction Type I error probability is

$$
P_{\theta_0}\left(\left|W_n\right|\geq z_{\alpha/2}\right)\to P_{\theta_0}\left(\left|Z\right|\geq z_{\alpha/2}\right)=\alpha
$$

and this is an asymptotically size *α* test.

• Now consider $\theta \neq \theta_0$ then

$$
W_n = \sqrt{n\hat{l}(\theta_0)} \left(\hat{\theta}_n - \theta_0\right) = \underbrace{\sqrt{n\hat{l}(\theta_0)} \left(\hat{\theta}_n - \theta\right)}_{\stackrel{D}{\longrightarrow} \mathcal{N}(0,1)} + \underbrace{\sqrt{n\hat{l}(\theta_0)} \left(\theta - \theta_0\right)}_{\stackrel{P}{\longrightarrow} \pm \infty}
$$

so

$$
P_{\theta}
$$
 (reject H_0) \rightarrow 1 as $n \rightarrow \infty$.

• Note that the (approximate) size α Wald test rejects H_0 : $\theta = \theta_0$ in favor of H_1 : $\theta \neq \theta_0$ if and only if $\theta_0 \notin C$ where

$$
C = \left(\widehat{\theta}_n - \frac{z_{\alpha/2}}{\sqrt{n \widehat{l}(\theta_0)}}, \widehat{\theta}_n + \frac{z_{\alpha/2}}{\sqrt{n \widehat{l}(\theta_0)}} \right).
$$

• Thus testing the hypothesis is equivalent to checking whether the null value is in the confidence interval.

- Similarly we can test H_0 : $\theta \le \theta_0$ against H_1 : $\theta > \theta_0$.
- In this case we use $W_n = \sqrt{n\widehat{I} \left(\theta_0 \right)} \left(\widehat{\theta}_n \theta_0 \right)$ and reject H_0 if $W_n \geq z_\alpha$.
- \bullet We have if $\theta = \theta_0$

$$
P_{\theta}\left(W_{n}\geq z_{\alpha}\right)\rightarrow P\left(Z\geq z_{\alpha}\right)=\alpha
$$

whereas if $\theta < \theta_0$ P_{θ} ($W_n \ge z_\alpha$) $\rightarrow 0$ and if $\theta > \theta_0$ P_{θ} ($W_n \geq z_{\alpha}$) \rightarrow 1.

- *Example*: Assume we have $X_i \stackrel{\text{i.i.d.}}{\sim} \text{Bernoulli}(p)$ and we want to test $H_0: p = p_0$ against $H_1: p \neq p_0$.
- We have for $S_n = \sum_{i=1}^n x_i$

$$
f(x|p) = p^{x}(1-p)^{1-x} \Rightarrow I(p) = S_n \log p + (n - S_n) \log (1-p)
$$

$$
I'(p) = \frac{S_n}{p} - \frac{(n - S_n)}{1-p} \Rightarrow \widehat{p}_n = \frac{S_n}{n}.
$$

o It is easy to check that

$$
\widehat{p}_n - p_0 \xrightarrow{D} \mathcal{N}\left(0, \frac{\sigma_0^2}{n}\right)
$$

where $\sigma_{0}^2\!=\!p_0\,(1-p_0).$ This quantity can be consistently estimated through $\sigma_n^2 = \widehat{p}_n \left(1 - \widehat{p}_n\right)$ so the Wald test is based on the statistic

$$
W_n=\frac{(\widehat{p}_n-p_0)}{\sqrt{\widehat{p}_n\left(1-\widehat{p}_n\right)/n}}.
$$

- Wald test is not limited to MLE estimate, you just need to know the asymptotic distribution of your test satistic.
- Example: Assume we have $X_1, ..., X_m$ and $Y_1, ..., Y_n$ be two independent samples from populations with mean μ_1 and $\mathsf{v}.$
- We write $\delta = \mu_1 \mu_2$ and we want to test $H_0: \delta = 0$ versus H_1 : $\delta \neq 0$.
- We build

$$
W = \frac{\overline{X} - \overline{Y}}{\sqrt{\frac{S_1^2}{m} + \frac{S_2^2}{m}}}
$$

where S_1^2 and S_2^2 are the sample variances.

Thanks to the CLT, we have $W \stackrel{\mathrm{D}}{\rightarrow} \mathcal{N} \left(0, 1 \right)$ as $m, n \to \infty$.

- Example (Comparing two prediction algorithms): We test a prediction algorithm on a test set of size m and the second prediction algorithm on a second test set of size n . Let X be the number of incorrect predictions for algorithm 1 and Y the number of incorrect prediction for algorithm 2. Then $X \sim Binomial(m, p_1)$ and $Y \sim Binomial(n, p_2)$.
- To test the null hypothesis H_0 : $\delta = p_1 p_2 = 0$ versus H_1 : $\delta \neq 0$ we note that $\hat{\delta} = \hat{p}_1 - \hat{p}_2$ with estimated standard error

$$
\sqrt{\frac{\widehat{\rho}_{1}\left(1-\widehat{\rho}_{1}\right)}{m}+\frac{\widehat{\rho}_{2}\left(1-\widehat{\rho}_{2}\right)}{n}}
$$

.

• The (approximate) size α test is to reject H_0 when

$$
|W| = \frac{|\widehat{p}_1 - \widehat{p}_2|}{\sqrt{\frac{\widehat{p}_1(1-\widehat{p}_1)}{m} + \frac{\widehat{p}_2(1-\widehat{p}_2)}{n}}} \geq z_{\alpha/2}
$$

as $W \stackrel{\text{D}}{\rightarrow} \mathcal{N}(0, 1)$ as $m, n \rightarrow \infty$ thanks to the CLT.

- In practice, we often have mispecified models! That is there does not exist any θ_0 such that $X_i \sim f(x|\theta_0)$ but $X_i \sim g$ [g being obviously unknown].
- In this case θ_0 is not the 'true' parameter but the parameter maximizing

$$
\int \log \frac{f(x|\theta)}{g(x)} \cdot g(x) dx \Rightarrow \int \frac{\partial \log f(x|\theta)}{\partial \theta} \Big|_{\theta=\theta_0} \cdot g(x) dx = 0
$$

The Wald test becomes incorrect as we do NOT have

$$
\sqrt{n}\left(\widehat{\theta}_{n}-\theta_{0}\right)\xrightarrow{\mathsf{D}}\mathcal{N}\left(0,I^{-1}\left(\theta_{0}\right)\right)
$$

• To correct it, let's go back to the derivation of the asymptotic normality

$$
0 = I'(\widehat{\theta}_n) \approx I'(\theta_0) + I''(\theta_0) (\widehat{\theta}_n - \theta_0)
$$

so

$$
\sqrt{n}\left(\widehat{\theta}_{n}-\theta_{0}\right) \approx \sqrt{n}\frac{-l'\left(\theta_{0}\right)}{l''\left(\theta_{0}\right)} = \frac{-l'\left(\theta_{0}\right)}{\sqrt{n}}\frac{n}{l''\left(\theta_{0}\right)}
$$

• We have by the law of large numbers

$$
\frac{I''(\theta)}{n} = \frac{1}{n} \sum_{i=1}^{n} \frac{\partial^2 \log f(X_i | \theta)}{\partial \theta^2} \xrightarrow{P} \int \frac{\partial^2 \log f(x | \theta)}{\partial \theta^2} g(x) dx
$$

• We also have

$$
\frac{I^{\prime}\left(\theta\right)}{\sqrt{n}}=\frac{1}{\sqrt{n}}\sum_{i=1}^{n}\frac{\partial\log f\left(\left.X_{i}\right|\theta\right)}{\partial\theta}
$$

where

$$
\text{var}\left[\frac{\partial \log f\left(X|\theta\right)}{\partial \theta}\right] = \int \frac{\partial \log f\left(x|\theta\right)^{2}}{\partial \theta} g\left(x\right) dx - \left(\int \frac{\partial \log f\left(x|\theta\right)}{\partial \theta} g\left(x\right) dx\right)^{2}
$$

So by the CLT

$$
\frac{I'\left(\theta_{0}\right)}{\sqrt{n}} \xrightarrow{D} \mathcal{N}\left(0, \int \frac{\partial \log f\left(x \mid \theta\right)^{2}}{\partial \theta} \mathcal{L}\left(x\right) dx \Bigg|_{\theta = \theta_{0}}\right)
$$

· By Slutzky's lemma

$$
\sqrt{n}\left(\widehat{\theta}_{n}-\theta_{0}\right) \rightarrow \mathcal{N}\left(0, \frac{\int \frac{\partial \log f(x|\theta)}{\partial \theta}\Big|_{\theta_{0}}^{2} \cdot g(x) dx}{\left(\int \frac{\partial^{2} \log f(x|\theta)}{\partial \theta^{2}}\Big|_{\theta_{0}} \cdot g(x) dx\right)^{2}}\right)
$$

The asymptotic variance can be estimated consistently from the data. We can derive a Wald test based on this asymptotic variance.

.

• This suggests developing a test for misspecification as

$$
\int \frac{\partial \log f(x|\theta)}{\partial \theta}^{2} f(x|\theta) dx + \left(\int \frac{\partial^{2} \log f(x|\theta)}{\partial \theta^{2}} f(x|\theta) dx \right) = 0
$$

• So we can propose the following test statistic

$$
T = \frac{1}{n} \sum_{i=1}^{n} \left. \frac{\partial \log f(x_i | \theta)}{\partial \theta}^{2} \right|_{\widehat{\theta}_n} + \frac{1}{n} \sum_{i=1}^{n} \left. \frac{\partial^2 \log f(x_i | \theta)}{\partial \theta^2} \right|_{\widehat{\theta}_n}
$$

which under H_0 : model specified is asymptotically Gaussian with zero-mean and variance which can be estimated consistently.

Rao Test

• We have under H_0 : $\theta = \theta_0$

$$
\frac{1}{\sqrt{n}}l'\left(\theta_0\right)\xrightarrow{D}\mathcal{N}\left(0, l\left(\theta_0\right)\right)
$$

where $I'\left(\theta\right) = \frac{\partial \log L\left(\theta | \mathbf{x}\right)}{\partial \theta}.$

• To prove this, remember that

$$
0 = I'(\widehat{\theta}_n) \approx I'(\theta_0) + I''(\theta_0) (\widehat{\theta}_n - \theta_0)
$$

thus

$$
\frac{1}{\sqrt{n}}I'(\theta_0) \approx -\frac{I''(\theta_0)}{\sqrt{n}}(\widehat{\theta}_n - \theta_0) = -\frac{I''(\theta_0)}{n}\sqrt{n}(\widehat{\theta}_n - \theta_0)
$$

where

$$
-\frac{l''\left(\theta_{0}\right)}{n}\xrightarrow{P} I\left(\theta_{0}\right) \text{ and } \sqrt{n}\left(\widehat{\theta}_{n}-\theta_{0}\right)\xrightarrow{D} \mathcal{N}\left(0, I^{-1}\left(\theta_{0}\right)\right).
$$

The result follows from Slutzky's lemma.

• This suggests defining the following Rao score statistic

$$
R_n = \frac{I'(\theta_0)}{\sqrt{n I(\theta_0)}}
$$

which converges in distribution to a standard normal under H_0 .

- A major advantage of the score statistics is that it does not require computing $\widehat{\theta}_n$. We could also replace $I(\theta_0)$ by a consistent estimate $\widehat{I} \left(\theta_0 \right)$. However using $I \left(\widehat{\theta}_n \right)$ would defeat the purpose of avoiding to compute $\widehat{\theta}_n$.
- A score test -also called Rao score test- is any test that rejects $H_0: \theta = \theta_0$ in favor of $H_1: \theta \neq \theta_0$ when $|R_n| \geq z_{\alpha/2}$.
- *Example*: Assume we have $X_i \stackrel{\text{i.i.d.}}{\sim} \text{Bernoulli}(p)$ and we want to test $H_0: p = p_0$ against $H_1: p \neq p_0$.
- We have for $S_n = \sum_{i=1}^n x_i$

$$
f(x|p) = p^x (1-p)^{1-x} \Rightarrow I(\lambda) = S_n \log p + (n - S_n) \log (1-p)
$$

\n
$$
I'(p) = \frac{S_n}{p} - \frac{(n - S_n)}{1-p} \Rightarrow \hat{p}_n = \frac{S_n}{n}.
$$

\n
$$
I''(p) = -\frac{S_n}{p^2} - \frac{(n - S_n)}{(1-p)^2}
$$

o It follows that

$$
I'(p) = \frac{n(\widehat{p}_n - p)}{p(1-p)}, I(p) = \frac{1}{p(1-p)}
$$

and

$$
R_n=\frac{l'\left(p_0\right)}{\sqrt{n l\left(p_0\right)}}=\frac{\widehat{p}_n-p_0}{\sqrt{p_0\left(1-p_0\right)/n}}.
$$

• In practice, for complex models, one would use

$$
R_n = \frac{I'(\theta_0)}{\sqrt{n\hat{I}(\theta_0)}}
$$

where

$$
\widehat{I}(\theta_0) = -\frac{1}{n} \sum_{i=1}^{n} \left. \frac{\partial^2 \log f(x_i | \theta)}{\partial \theta^2} \right|_{\theta_0} \xrightarrow{P} I(\theta_0)
$$

which is consistent thanks to Slutzky.

• However, once more one has to be careful for misspecified models

o Indeed we have

$$
\frac{1}{\sqrt{n}}I'(\theta_0) \approx -\frac{I''(\theta_0)}{\sqrt{n}}(\widehat{\theta}_n - \theta_0) = -\frac{I''(\theta_0)}{n}\sqrt{n}(\widehat{\theta}_n - \theta_0)
$$

where

$$
-\frac{I''(\theta_0)}{n} \xrightarrow{P} \int \frac{\partial^2 \log f(x|\theta)}{\partial \theta^2} \bigg|_{\theta=\theta_0} g(x) dx
$$

and

$$
\sqrt{n}\left(\widehat{\theta}_{n}-\theta_{0}\right) \xrightarrow{D} \mathcal{N}\left(0, \frac{\int \frac{\partial \log f(x|\theta)}{\partial \theta}^{2} \cdot g(x) dx \Big|_{\theta=\theta_{0}}}{\left(\int \frac{\partial^{2} \log f(x|\theta)}{\partial \theta^{2}} \Big|_{\theta=\theta_{0}} \cdot g(x) dx\right)^{2}}\right)
$$

so

$$
\frac{1}{\sqrt{n}}l'\left(\theta_{0}\right)\xrightarrow{D}\mathcal{N}\left(0,\int\frac{\partial\log f\left(x\right|\theta\right)}{\partial\theta}\bigg|_{\theta_{0}}^{2}\cdot g\left(x\right)dx\right)
$$

• Thus if you use Rao test for misspecified model, you have to use the following consistent estimate of the asymptotic variance

$$
\frac{1}{n}\sum_{i=1}^{n}\left.\frac{\partial \log f\left(x_{i}\right|\theta\right)}{\partial \theta}\right|_{\theta_{0}}^{2}\xrightarrow{D}\int\left.\frac{\partial \log f\left(x\right|\theta\right)}{\partial \theta}\right|_{\theta_{0}}^{2}\cdot g\left(x\right)dx
$$

If you use the standard estimate $-\frac{1}{n}$ n $\sum_{i=1}$ $\frac{\partial^2 \log f(x_i|\theta)}{\partial x_i}$ *∂θ*² $\Big|_{\theta_0}$, then you will get a wrong result.

Likelihood Ratio Test

o The LR test is based on

$$
\Delta_n = I\left(\widehat{\theta}_n\right) - I\left(\theta_0\right) = \log \left(\frac{\sup L\left(\left.\theta\right|\mathbf{x}\right)}{L\left(\left.\theta_0\right|\mathbf{x}\right)}\right) \geq 0.
$$

If we perform a Taylor expansion of $\displaystyle l'\left(\widehat {\theta }_n\right)=0$ around $\theta _0$ then

$$
I'\left(\widehat{\theta}_0\right) = \left(\widehat{\theta}_n - \theta_0\right) \left(-I''\left(\theta_0\right) + o\left(1\right)\right). \tag{1}
$$

By performing another Taylor expansion of $I\left(\widehat{\theta}_n\right)$ around θ_0 then

$$
\Delta_n = \left(\widehat{\theta}_n - \theta_0\right) I'(\theta_0) + \frac{1}{2} \left(\widehat{\theta}_n - \theta_0\right)^2 \left[I''(\theta_0) + o(1)\right]. \quad (2)
$$

Hence, by substituting [\(1\)](#page-20-0) in [\(2\)](#page-20-1), then

$$
\Delta_n = n \left(\widehat{\theta}_n - \theta_0 \right)^2 \left\{ -\frac{1}{n} I''\left(\theta_0 \right) + \frac{1}{2n} I''\left(\theta_0 \right) + o\left(\frac{1}{n} \right) \right\}.
$$

 \bullet By Slutsky's theorem, this implies that under H_0

$$
2\Delta_n \stackrel{\mathsf{D}}{\rightarrow} \chi_1^2.
$$

- Noting that the 1α quantile of a χ_1^2 distribution is $z_{\alpha/2}^2$, we can now define the LR test.
- A LR test is any test that rejects H_0 : $\theta = \theta_0$ in favor of H_1 : $\theta \neq \theta_0$ when $2\Delta_n \geq z_{\alpha/2}^2$ or, equivalently, when $\sqrt{2\Delta_n} \geq z_{\alpha/2}$; i.e. we reject for small values of the LR.
- Example: Assume we have $X_i \stackrel{\text{i.i.d.}}{\sim} \mathcal{P}(\lambda)$ and we want to test H_0 : $\lambda = \lambda_0$ against H_1 : $\lambda \neq \lambda_0$.
- We have for $S_n = \sum_{i=1}^n x_i$

$$
f(x|\lambda) = \exp(-\lambda) \frac{\lambda^x}{x!} \Rightarrow I(\lambda) = -n\lambda + S_n \log \lambda - \left(\sum_{i=1}^n x_i!\right)
$$

$$
I'(\lambda) = -n + \frac{S_n}{\lambda}, I''(\lambda) = -\frac{S_n}{\lambda^2}.
$$

It follows that $\widehat{\lambda}_n = \frac{S_n}{n}$ and

$$
\Delta_n = n\left(\lambda_0 - \widehat{\lambda}_n\right) + S_n \log \frac{\widehat{\lambda}_n}{\lambda_0}.
$$

• We can show that (when there is no misspecification)

$$
R_n \stackrel{\mathsf{P}}{\rightarrow} W_n,
$$

$$
W_n^2 \stackrel{\mathsf{P}}{\rightarrow} 2\Delta_n.
$$

- The tests are thus asymptotically equivalent in the sense that under H₀ they reach the same decision with probability 1 as $n \rightarrow \infty$.
- \bullet For a finite sample size n, they have some relative advantages and disadvantages with respect to one another.
- It is easy to create one-sided Wald and score tests.
- **•** The score test does not require $\widehat{\theta}_n$ whereas the other two tests do.
- The Wald test is most easily interpretable and yields immediate confidence intervals.
- The score test and LR test are invariant under reparametrization, whereas the Wald test is not.

• Example: Assume
$$
X_i \stackrel{\text{i.i.d.}}{\sim} f(x|\theta)
$$
 where
\n $f(x|\theta) = \theta \exp(-x\theta) \mathbb{I} \{x > 0\}$. Then
\n $I(\theta) = n (\log \theta - \theta \overline{X}_n)$

which yields

$$
I'(\theta) = n\left(\frac{1}{\theta} - \overline{X}_n\right) \text{ and } I''(\theta) = -\frac{n}{\theta^2}.
$$

• We also obtain

$$
\widehat{\theta}_n = \frac{1}{\overline{X}_n}, \ I(\theta) = \theta^{-2}.
$$

• It follows that

$$
W_n = \frac{\sqrt{n}}{\theta_0} \left(\frac{1}{\overline{X}_n} - \theta_0 \right),
$$

\n
$$
R_n = \theta_0 \sqrt{n} \left(\frac{1}{\theta_0} - \overline{X}_n \right) = \frac{W_n}{\theta_0 \overline{X}_n},
$$

\n
$$
\Delta_n = n \left\{ \overline{X}_n \left(\overline{X}_n - \theta_0 \right) - \log \left(\theta_0 \overline{X}_n \right) \right\}.
$$

Example: Assume $X_i \stackrel{\text{i.i.d.}}{\sim} f(x|\theta)$ where $f(x|\theta) = \theta c^{\theta} x^{-(\theta+1)} \mathbb{I} \{x > c\}$ (Pareto distribution)

where c is a known constant and *θ* is unknown.

We have for $S_n = \sum_{i=1}^n \log(x_i)$

$$
I(\theta) = n(\log \theta + \theta \log c) - (\theta + 1) S_n,
$$

$$
I'(\theta) = n\left(\frac{1}{\theta} + \log c\right) - S_n, I''(\theta) = -\frac{n}{\theta^2}.
$$

Thus we have $\widehat{\theta}_n = \frac{n}{S_n - n \log c}$, $I(\theta) = \theta^{-2}$ and it follows that

$$
W_n = \frac{\sqrt{n}}{\theta_0} \left(\frac{n}{S_n - n \log c} - \theta_0 \right),
$$

\n
$$
R_n = \sqrt{n} \theta_0 \left(\left(\frac{1}{\theta_0} + \log c \right) - S_n \right),
$$

\n
$$
\Delta_n = n \left(\log \frac{\widehat{\theta}_n}{\theta_0} + \left(\widehat{\theta}_n - \theta_0 \right) \log c \right) - \left(\widehat{\theta}_n - \theta_0 \right) S_n.
$$

When $\theta \in \mathbb{R}^d$, then the Wald, Rao and LR tests can be straightforwardly extended

$$
W_n : = n \left(\widehat{\theta}_n - \theta_0 \right)^{\top} I(\theta_0) \left(\widehat{\theta}_n - \theta_0 \right) \xrightarrow{D} \chi_d^2,
$$

\n
$$
R_n : = \frac{1}{n} \nabla I(\theta_0)^{\top} I^{-1}(\theta_0) \nabla I(\theta_0) \xrightarrow{D} \chi_d^2,
$$

\n
$$
\Delta_n : = I(\widehat{\theta}_n) - I(\theta_0) \xrightarrow{D} \frac{1}{2} \chi_d^2
$$

- Therefore, if c_{α}^{d} denotes the 1α quantile of the χ_{d}^{2} distribution, then we reject H_0 when $W_n \geq c_\alpha^d$, $R_n \geq c_\alpha^d$ and $2\Delta_n \geq c_\alpha^d$.
- As in the scalar case, in the Wald test, we can subsitute to $I(\theta_0)$ a consistent estimate.

• Example: Assume we observe a vector $X = (X_1, ..., X_k)$ where $X_j \in \{0,1\}$, $\sum_{j=1}^k X_j = 1$ with

$$
f(x | p_1, ..., p_{k-1}) = \left(\prod_{j=1}^{k-1} p_j^{x_j}\right) \left(1 - \sum_{j=1}^{k-1} p_j\right)^{x_k}
$$

where $p_j>0$ and $p_k:=1-\sum_{j=1}^{k-1}p_j< 1.$ We have $\theta = (p_1, ..., p_{k-1}).$

We have for n observations $X^1,X^2,...,X^n$

$$
I(\theta) = \sum_{j=1}^{k} t_j \log p_j = \sum_{j=1}^{k-1} t_j \log p_j + t_k \log \left(1 - \sum_{j=1}^{k-1} p_j \right),
$$

$$
\frac{\partial I(\theta)}{\partial p_j} = \frac{t_j}{p_j} - \frac{t_k}{p_k}, \frac{\partial^2 I(\theta)}{\partial p_j^2} = -\frac{t_j}{p_j^2} - \frac{t_k}{p_k^2},
$$

$$
\frac{\partial^2 I(\theta)}{\partial p_j \partial p_l} = -\frac{t_k}{p_k^2}, j \neq l < k.
$$

where
$$
t_j = \sum_{i=1}^n x_j^i
$$
.

• Recall that X_i has a Bernoulli distribution with mean p_i so

$$
I(\theta) = \begin{bmatrix} p_1^{-1} + p_k^{-1} & p_k^{-1} & p_k^{-1} \\ p_k^{-1} & p_2^{-1} + p_k^{-1} & \vdots \\ \vdots & \vdots & \vdots \\ p_k^{-1} & \vdots & \vdots \\ \vdots & \vdots & \vdots \\ p_{k-1}^{-1} + p_k^{-1} \end{bmatrix}
$$

o It follows that

$$
W_n = n \left(\widehat{\theta}_n - \theta_0 \right) I(\theta_0) \left(\widehat{\theta}_n - \theta_0 \right),
$$

$$
R_n = \frac{1}{n} \nabla I(\theta_0)^\top I^{-1}(\theta_0) \nabla I(\theta_0).
$$

After tiedous calculations, it can be shown that

$$
W_n = R_n = \sum_{j=1}^k \frac{(t_j - np_i)^2}{np_i}
$$

which is the usual Pearson chi-square test whereas $\Delta_n = n \sum_{j=1}^k \mathcal t_j \log \frac{\widehat{\rho}_j}{\rho_j}.$